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### What is "[Embedded - Microcontrollers](#)"?

"[Embedded - Microcontrollers](#)" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

### Applications of "[Embedded - Microcontrollers](#)"

#### Details

Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I <sup>2</sup> C, IrDA, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, POR, PWM, WDT
Number of I/O	51
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	6K x 8
RAM Size	20K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 16x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-UFBGA
Supplier Device Package	64-UFBGA (5x5)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l072rbi6tr">https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l072rbi6tr</a>

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## 2 Description

The ultra-low-power STM32L072xx microcontrollers incorporate the connectivity power of the universal serial bus (USB 2.0 crystal-less) with the high-performance ARM® Cortex®-M0+ 32-bit RISC core operating at a 32 MHz frequency, a memory protection unit (MPU), high-speed embedded memories (up to 192 Kbytes of Flash program memory, 6 Kbytes of data EEPROM and 20 Kbytes of RAM) plus an extensive range of enhanced I/Os and peripherals.

The STM32L072xx devices provide high power efficiency for a wide range of performance. It is achieved with a large choice of internal and external clock sources, an internal voltage adaptation and several low-power modes.

The STM32L072xx devices offer several analog features, one 12-bit ADC with hardware oversampling, two DACs, two ultra-low-power comparators, several timers, one low-power timer (LPTIM), four general-purpose 16-bit timers and two basic timer, one RTC and one SysTick which can be used as timebases. They also feature two watchdogs, one watchdog with independent clock and window capability and one window watchdog based on bus clock.

Moreover, the STM32L072xx devices embed standard and advanced communication interfaces: up to three I2Cs, two SPIs, one I2S, four USARTs, a low-power UART (LPUART), and a crystal-less USB. The devices offer up to 24 capacitive sensing channels to simply add touch sensing functionality to any application.

The STM32L072xx also include a real-time clock and a set of backup registers that remain powered in Standby mode.

The ultra-low-power STM32L072xx devices operate from a 1.8 to 3.6 V power supply (down to 1.65 V at power down) with BOR and from a 1.65 to 3.6 V power supply without BOR option. They are available in the -40 to +125 °C temperature range. A comprehensive set of power-saving modes allows the design of low-power applications.



**Table 5. Functionalities depending on the working mode  
(from Run/active down to standby) (continued)<sup>(1)(2)</sup>**

IPs	Run/Active	Sleep	Low-power run	Low-power sleep	Stop		Standby	
					Wakeup capability		Wakeup capability	
Temperature sensor	O	O	O	O	O		--	
Comparators	O	O	O	O	O	O	--	
16-bit timers	O	O	O	O	--		--	
LPTIMER	O	O	O	O	O	O		
IWDG	O	O	O	O	O	O	O	O
WWDG	O	O	O	O	--		--	
Touch sensing controller (TSC)	O	O	--	--	--		--	
SysTick Timer	O	O	O	O			--	
GPIOs	O	O	O	O	O	O		2 pins
Wakeup time to Run mode	0 $\mu$ s	0.36 $\mu$ s	3 $\mu$ s	32 $\mu$ s	3.5 $\mu$ s		50 $\mu$ s	
Consumption $V_{DD}=1.8$ to $3.6$ V (Typ)	Down to 140 $\mu$ A/MHz (from Flash memory)	Down to 37 $\mu$ A/MHz (from Flash memory)	Down to 8 $\mu$ A	Down to 4.5 $\mu$ A	0.4 $\mu$ A (No RTC) $V_{DD}=1.8$ V		0.28 $\mu$ A (No RTC) $V_{DD}=1.8$ V	
					0.8 $\mu$ A (with RTC) $V_{DD}=1.8$ V		0.65 $\mu$ A (with RTC) $V_{DD}=1.8$ V	
					0.4 $\mu$ A (No RTC) $V_{DD}=3.0$ V		0.29 $\mu$ A (No RTC) $V_{DD}=3.0$ V	
					1 $\mu$ A (with RTC) $V_{DD}=3.0$ V		0.85 $\mu$ A (with RTC) $V_{DD}=3.0$ V	

- Legend:  
 "Y" = Yes (enable).  
 "O" = Optional can be enabled/disabled by software)  
 "-" = Not available
- The consumption values given in this table are preliminary data given for indication. They are subject to slight changes.
- Some peripherals with wakeup from Stop capability can request HSI to be enabled. In this case, HSI is woken up by the peripheral, and only feeds the peripheral which requested it. HSI is automatically put off when the peripheral does not need it anymore.
- UART and LPUART reception is functional in Stop mode. It generates a wakeup interrupt on Start. To generate a wakeup on address match or received frame event, the LPUART can run on LSE clock while the UART has to wake up or keep running the HSI clock.
- I2C address detection is functional in Stop mode. It generates a wakeup interrupt in case of address match. It will wake up the HSI during reception.

### 3.3 ARM® Cortex®-M0+ core with MPU

The Cortex-M0+ processor is an entry-level 32-bit ARM Cortex processor designed for a broad range of embedded applications. It offers significant benefits to developers, including:

- a simple architecture that is easy to learn and program
- ultra-low power, energy-efficient operation
- excellent code density
- deterministic, high-performance interrupt handling
- upward compatibility with Cortex-M processor family
- platform security robustness, with integrated Memory Protection Unit (MPU).

The Cortex-M0+ processor is built on a highly area and power optimized 32-bit processor core, with a 2-stage pipeline Von Neumann architecture. The processor delivers exceptional energy efficiency through a small but powerful instruction set and extensively optimized design, providing high-end processing hardware including a single-cycle multiplier.

The Cortex-M0+ processor provides the exceptional performance expected of a modern 32-bit architecture, with a higher code density than other 8-bit and 16-bit microcontrollers.

Owing to its embedded ARM core, the STM32L072xx are compatible with all ARM tools and software.

#### Nested vectored interrupt controller (NVIC)

The ultra-low-power STM32L072xx embed a nested vectored interrupt controller able to handle up to 32 maskable interrupt channels and 4 priority levels.

The Cortex-M0+ processor closely integrates a configurable Nested Vectored Interrupt Controller (NVIC), to deliver industry-leading interrupt performance. The NVIC:

- includes a Non-Maskable Interrupt (NMI)
- provides zero jitter interrupt option
- provides four interrupt priority levels

The tight integration of the processor core and NVIC provides fast execution of Interrupt Service Routines (ISRs), dramatically reducing the interrupt latency. This is achieved through the hardware stacking of registers, and the ability to abandon and restart load-multiple and store-multiple operations. Interrupt handlers do not require any assembler wrapper code, removing any code overhead from the ISRs. Tail-chaining optimization also significantly reduces the overhead when switching from one ISR to another.

To optimize low-power designs, the NVIC integrates with the sleep modes, that include a deep sleep function that enables the entire device to enter rapidly stop or standby mode.

This hardware block provides flexible interrupt management features with minimal interrupt latency.

### 3.6 Low-power real-time clock and backup registers

The real time clock (RTC) and the 5 backup registers are supplied in all modes including standby mode. The backup registers are five 32-bit registers used to store 20 bytes of user application data. They are not reset by a system reset, or when the device wakes up from Standby mode.

The RTC is an independent BCD timer/counter. Its main features are the following:

- Calendar with subsecond, seconds, minutes, hours (12 or 24 format), week day, date, month, year, in BCD (binary-coded decimal) format
- Automatically correction for 28, 29 (leap year), 30, and 31 day of the month
- Two programmable alarms with wake up from Stop and Standby mode capability
- Periodic wakeup from Stop and Standby with programmable resolution and period
- On-the-fly correction from 1 to 32767 RTC clock pulses. This can be used to synchronize it with a master clock.
- Reference clock detection: a more precise second source clock (50 or 60 Hz) can be used to enhance the calendar precision.
- Digital calibration circuit with 1 ppm resolution, to compensate for quartz crystal inaccuracy
- 2 anti-tamper detection pins with programmable filter. The MCU can be woken up from Stop and Standby modes on tamper event detection.
- Timestamp feature which can be used to save the calendar content. This function can be triggered by an event on the timestamp pin, or by a tamper event. The MCU can be woken up from Stop and Standby modes on timestamp event detection.

The RTC clock sources can be:

- A 32.768 kHz external crystal
- A resonator or oscillator
- The internal low-power RC oscillator (typical frequency of 37 kHz)
- The high-speed external clock

### 3.7 General-purpose inputs/outputs (GPIOs)

Each of the GPIO pins can be configured by software as output (push-pull or open-drain), as input (with or without pull-up or pull-down) or as peripheral alternate function. Most of the GPIO pins are shared with digital or analog alternate functions, and can be individually remapped using dedicated alternate function registers. All GPIOs are high current capable. Each GPIO output, speed can be slowed (40 MHz, 10 MHz, 2 MHz, 400 kHz). The alternate function configuration of I/Os can be locked if needed following a specific sequence in order to avoid spurious writing to the I/O registers. The I/O controller is connected to a dedicated IO bus with a toggling speed of up to 32 MHz.

#### Extended interrupt/event controller (EXTI)

The extended interrupt/event controller consists of 29 edge detector lines used to generate interrupt/event requests. Each line can be individually configured to select the trigger event (rising edge, falling edge, both) and can be masked independently. A pending register maintains the status of the interrupt requests. The EXTI can detect an external line with a pulse width shorter than the Internal APB2 clock period. Up to 84 GPIOs can be connected to the 16 configurable interrupt/event lines. The 13 other lines are connected to PVD, RTC, USB, USARTs, I2C, LPUART, LPTIMER or comparator events.

Table 19. Alternate functions port C

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
		SPI1/SPI2/I2S2/ USART1/2/ LPUART1/USB/ LPTIM1/TSC/ TIM2/21/22/ EVENTOUT/ SYS_AF	SPI1/SPI2/I2S2/I2C1/ TIM2/21	SPI1/SPI2/I2S2/ LPUART1/ USART5/USB/ LPTIM1/TIM2/3 /EVENTOUT/SYS_AF	I2C1/TSC/ EVENTOUT	I2C1/USART1/2/ LPUART1/ TIM3/22/ EVENTOUT	SPI2/I2S2 /I2C2/ USART1/ TIM2/21/22	I2C1/2/ LPUART1/ USART4/ UASRT5/TIM21/E VENTOUT	I2C3/LPUART1/ COMP1/2/ TIM3
Port C	PC0	LPTIM1_IN1		EVENTOUT	TSC_G7_IO1			LPUART1_RX	I2C3_SCL
	PC1	LPTIM1_OUT		EVENTOUT	TSC_G7_IO2			LPUART1_TX	I2C3_SDA
	PC2	LPTIM1_IN2		SPI2_MISO/ I2S2_MCK	TSC_G7_IO3				
	PC3	LPTIM1_ETR		SPI2_MOSI/ I2S2_SD	TSC_G7_IO4				
	PC4	EVENTOUT		LPUART1_TX					
	PC5			LPUART1_RX	TSC_G3_IO1				
	PC6	TIM22_CH1		TIM3_CH1	TSC_G8_IO1				
	PC7	TIM22_CH2		TIM3_CH2	TSC_G8_IO2				
	PC8	TIM22_ETR		TIM3_CH3	TSC_G8_IO3				
	PC9	TIM21_ETR		USB_OE/TIM3_CH4	TSC_G8_IO4				I2C3_SDA
	PC10	LPUART1_TX						USART4_TX	
	PC11	LPUART1_RX						USART4_RX	
	PC12			USART5_TX				USART4_CK	
	PC13								
	PC14								
	PC15								





Table 20. Alternate functions port D

Port		AF0	AF1	AF2	AF3	AF4	AF5	AF6	AF7
		SPI1/SPI2/I2S2/ USART1/2/ LPUART1/USB/ LPTIM1/TSC/ TIM2/21/22/ EVENTOUT/ SYS_AF	SPI1/SPI2/I2S2/I2C1/ TIM2/21	SPI1/SPI2/I2S2/ LPUART1/ USART5/USB/ LPTIM1/TIM2/3 /EVENTOUT/ SYS_AF	I2C1/TSC/ EVENTOUT	I2C1/USART1/2/ LPUART1/ TIM3/22/ EVENTOUT	SPI2/I2S2 /I2C2/ USART1/ TIM2/21/22	I2C1/2/ LPUART1/ USART4/ UASRT5/TIM21/E VENTOUT	I2C3/LPUART1/ COMP1/2/TIM3
Port D	PD0	TIM21_CH1	SPI2_NSS/I2S2_WS	-	-	-	-	-	-
	PD1	-	SPI2_SCK/I2S2_CK	-	-	-	-	-	-
	PD2	LPUART1_RTS_ DE		TIM3_ETR	-	-	-	USART5_RX	-
	PD3	USART2_CTS		SPI2_MISO/ I2S2_MCK	-	-	-	-	-
	PD4	USART2_RTS_D E	SPI2_MOSI/I2S2_SD	-	-	-	-	-	-
	PD5	USART2_TX	-	-	-	-	-	-	-
	PD6	USART2_RX	-	-	-	-	-	-	-
	PD7	USART2_CK	TIM21_CH2	-	-	-	-	-	-
	PD8	LPUART1_TX		-	-	-	-	-	-
	PD9	LPUART1_RX		-	-	-	-	-	-
	PD10	-		-	-	-	-	-	-
	PD11	LPUART1_CTS		-	-	-	-	-	-
	PD12	LPUART1_RTS_ DE		-	-	-	-	-	-
	PD13	-		-	-	-	-	-	-
	PD14	-		-	-	-	-	-	-
	PD15	USB_CRD_SYNC		-	-	-	-	-	-

## 6 Electrical characteristics

### 6.1 Parameter conditions

Unless otherwise specified, all voltages are referenced to  $V_{SS}$ .

#### 6.1.1 Minimum and maximum values

Unless otherwise specified the minimum and maximum values are guaranteed in the worst conditions of ambient temperature, supply voltage and frequencies by tests in production on 100% of the devices with an ambient temperature at  $T_A = 25\text{ }^{\circ}\text{C}$  and  $T_A = T_{A\text{max}}$  (given by the selected temperature range).

Data based on characterization results, design simulation and/or technology characteristics are indicated in the table footnotes and are not tested in production. Based on characterization, the minimum and maximum values refer to sample tests and represent the mean value plus or minus three times the standard deviation ( $\text{mean} \pm 3\sigma$ ).

#### 6.1.2 Typical values

Unless otherwise specified, typical data are based on  $T_A = 25\text{ }^{\circ}\text{C}$ ,  $V_{DD} = 3.6\text{ V}$  (for the  $1.65\text{ V} \leq V_{DD} \leq 3.6\text{ V}$  voltage range). They are given only as design guidelines and are not tested.

Typical ADC accuracy values are determined by characterization of a batch of samples from a standard diffusion lot over the full temperature range, where 95% of the devices have an error less than or equal to the value indicated ( $\text{mean} \pm 2\sigma$ ).

#### 6.1.3 Typical curves

Unless otherwise specified, all typical curves are given only as design guidelines and are not tested.

#### 6.1.4 Loading capacitor

The loading conditions used for pin parameter measurement are shown in [Figure 12](#).

#### 6.1.5 Pin input voltage

The input voltage measurement on a pin of the device is described in [Figure 13](#).

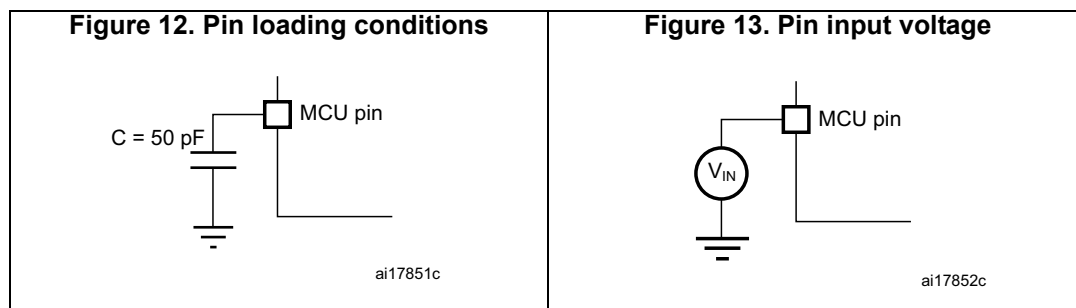


Figure 20.  $I_{DD}$  vs  $V_{DD}$ , at  $T_A = 25/55/85/105/125\text{ }^{\circ}\text{C}$ , Stop mode with RTC disabled, all clocks off

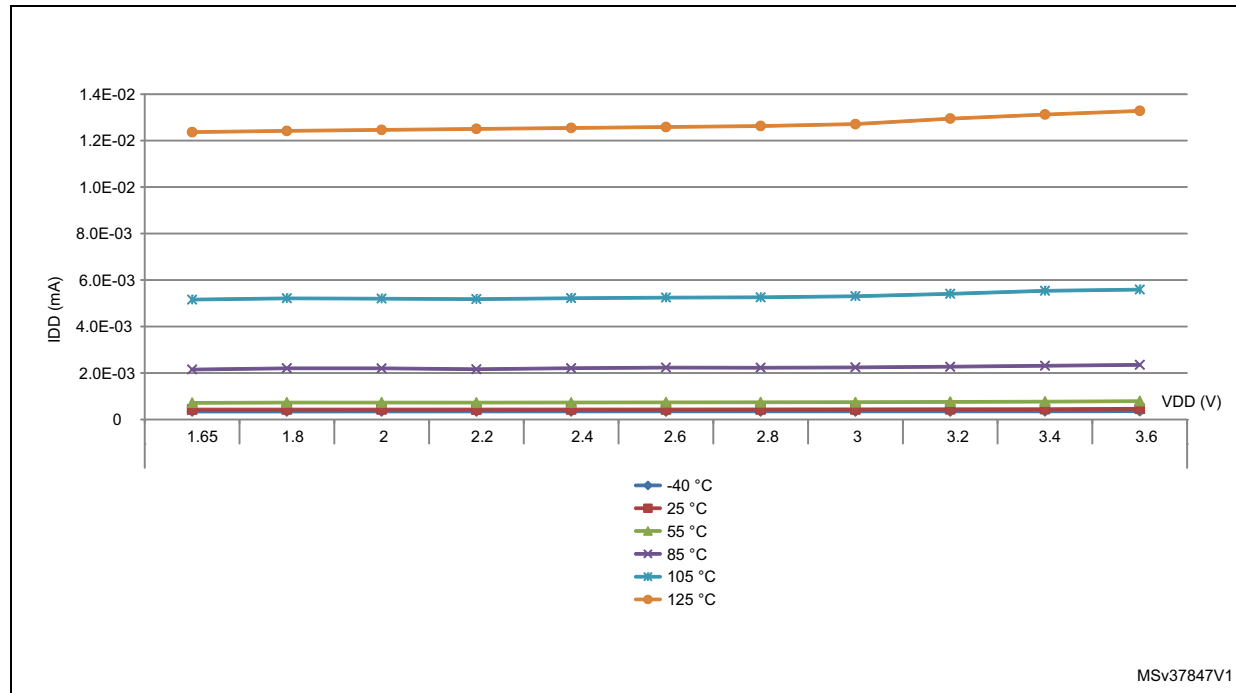


Table 38. Typical and maximum current consumptions in Standby mode

Symbol	Parameter	Conditions		Typ	Max <sup>(1)</sup>	Unit
$I_{DD}$ (Standby)	Supply current in Standby mode	Independent watchdog and LSI enabled	$T_A = -40\text{ to }25\text{ }^{\circ}\text{C}$	0,855	1,70	$\mu\text{A}$
			$T_A = 55\text{ }^{\circ}\text{C}$	-	2,90	
			$T_A = 85\text{ }^{\circ}\text{C}$	-	3,30	
			$T_A = 105\text{ }^{\circ}\text{C}$	-	4,10	
			$T_A = 125\text{ }^{\circ}\text{C}$	-	8,50	
		Independent watchdog and LSI off	$T_A = -40\text{ to }25\text{ }^{\circ}\text{C}$	0,29	0,60	
			$T_A = 55\text{ }^{\circ}\text{C}$	0,32	1,20	
			$T_A = 85\text{ }^{\circ}\text{C}$	0,5	2,30	
			$T_A = 105\text{ }^{\circ}\text{C}$	0,94	3,00	
			$T_A = 125\text{ }^{\circ}\text{C}$	2,6	7,00	

1. Guaranteed by characterization results at 125 °C, unless otherwise specified

### On-chip peripheral current consumption

The current consumption of the on-chip peripherals is given in the following tables. The MCU is placed under the following conditions:

- all I/O pins are in input mode with a static value at  $V_{DD}$  or  $V_{SS}$  (no load)
- all peripherals are disabled unless otherwise mentioned
- the given value is calculated by measuring the current consumption
  - with all peripherals clocked off
  - with only one peripheral clocked on

**Table 40. Peripheral current consumption in Run or Sleep mode<sup>(1)</sup>**

Peripheral		Typical consumption, $V_{DD} = 3.0\text{ V}$ , $T_A = 25\text{ °C}$				Unit
		Range 1, $V_{CORE}=1.8\text{ V}$ $VOS[1:0] = 01$	Range 2, $V_{CORE}=1.5\text{ V}$ $VOS[1:0] = 10$	Range 3, $V_{CORE}=1.2\text{ V}$ $VOS[1:0] = 11$	Low-power sleep and run	
APB1	CRS	2.5	2	2	2	$\mu\text{A}/\text{MHz}$ ( $f_{HCLK}$ )
	DAC1/2	4	3.5	3	2.5	
	I2C1	11	9.5	7.5	9	
	I2C3	11	9	7	9	
	LPTIM1	10	8.5	6.5	8	
	LPUART1	8	6.5	5.5	6	
	SPI2	9	4.5	3.5	4	
	USB	8.5	4.5	4	4.5	
	USART2	14.5	12	9.5	11	
	USART4	5	4	3	5	
	USART5	5	4	3	5	
	TIM2	10.5	8.5	7	9	
	TIM3	12	10	8	11	
	TIM6	3.5	3	2.5	2	
	TIM7	3.5	3	2.5	2	
	WWDG	3	2	2	2	

Table 41. Peripheral current consumption in Stop and Standby mode<sup>(1)</sup>

Symbol	Peripheral	Typical consumption, T <sub>A</sub> = 25 °C		Unit
		V <sub>DD</sub> =1.8 V	V <sub>DD</sub> =3.0 V	
I <sub>DD</sub> (PVD / BOR)	-	0.7	1.2	μA
I <sub>REFINT</sub>	-	-	1.7	
-	LSE Low drive <sup>(2)</sup>	0.11	0,13	
-	LSI	0.27	0.31	
-	IWDG	0.2	0.3	
-	LPTIM1, Input 100 Hz	0.01	0,01	
-	LPTIM1, Input 1 MHz	11	12	
-	LPUART1	-	0,5	
-	RTC	0.16	0,3	

1. LPTIM, LPUART peripherals can operate in Stop mode but not in Standby mode.

2. LSE Low drive consumption is the difference between an external clock on OSC32\_IN and a quartz between OSC32\_IN and OSC32\_OUT.-

### 6.3.5 Wakeup time from low-power mode

The wakeup times given in the following table are measured with the MSI or HSI16 RC oscillator. The clock source used to wake up the device depends on the current operating mode:

- Sleep mode: the clock source is the clock that was set before entering Sleep mode
- Stop mode: the clock source is either the MSI oscillator in the range configured before entering Stop mode, the HSI16 or HSI16/4.
- Standby mode: the clock source is the MSI oscillator running at 2.1 MHz

All timings are derived from tests performed under ambient temperature and V<sub>DD</sub> supply voltage conditions summarized in [Table 26](#).

Table 42. Low-power mode wakeup timings

Symbol	Parameter	Conditions	Typ	Max	Unit
t <sub>WUSLEEP</sub>	Wakeup from Sleep mode	f <sub>HCLK</sub> = 32 MHz	7	8	Number of clock cycles
t <sub>WUSLEEP_LP</sub>	Wakeup from Low-power sleep mode, f <sub>HCLK</sub> = 262 kHz	f <sub>HCLK</sub> = 262 kHz Flash memory enabled	7	8	
		f <sub>HCLK</sub> = 262 kHz Flash memory switched OFF	9	10	

### 6.3.7 Internal clock source characteristics

The parameters given in [Table 47](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 26](#).

#### High-speed internal 16 MHz (HSI16) RC oscillator

Table 47. 16 MHz HSI16 oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$f_{\text{HSI16}}$	Frequency	$V_{DD} = 3.0 \text{ V}$	-	16	-	MHz
$\text{TRIM}^{(1)(2)}$	HSI16 user-trimmed resolution	Trimming code is not a multiple of 16	-	$\pm 0.4$	0.7	%
		Trimming code is a multiple of 16	-	-	$\pm 1.5$	%
$\text{ACC}_{\text{HSI16}}^{(2)}$	Accuracy of the factory-calibrated HSI16 oscillator	$V_{DDA} = 3.0 \text{ V}$ , $T_A = 25 \text{ }^\circ\text{C}$	-1 <sup>(3)</sup>	-	1 <sup>(3)</sup>	%
		$V_{DDA} = 3.0 \text{ V}$ , $T_A = 0 \text{ to } 55 \text{ }^\circ\text{C}$	-1.5	-	1.5	%
		$V_{DDA} = 3.0 \text{ V}$ , $T_A = -10 \text{ to } 70 \text{ }^\circ\text{C}$	-2	-	2	%
		$V_{DDA} = 3.0 \text{ V}$ , $T_A = -10 \text{ to } 85 \text{ }^\circ\text{C}$	-2.5	-	2	%
		$V_{DDA} = 3.0 \text{ V}$ , $T_A = -10 \text{ to } 105 \text{ }^\circ\text{C}$	-4	-	2	%
		$V_{DDA} = 1.65 \text{ V to } 3.6 \text{ V}$ $T_A = -40 \text{ to } 125 \text{ }^\circ\text{C}$	-5.45	-	3.25	%
$t_{\text{SU(HSI16)}}^{(2)}$	HSI16 oscillator startup time	-	-	3.7	6	$\mu\text{s}$
$I_{\text{DD(HSI16)}}^{(2)}$	HSI16 oscillator power consumption	-	-	100	140	$\mu\text{A}$

1. The trimming step differs depending on the trimming code. It is usually negative on the codes which are multiples of 16 (0x00, 0x10, 0x20, 0x30...0xE0).
2. Guaranteed by characterization results.
3. Guaranteed by test in production.

Figure 25. HSI16 minimum and maximum value versus temperature

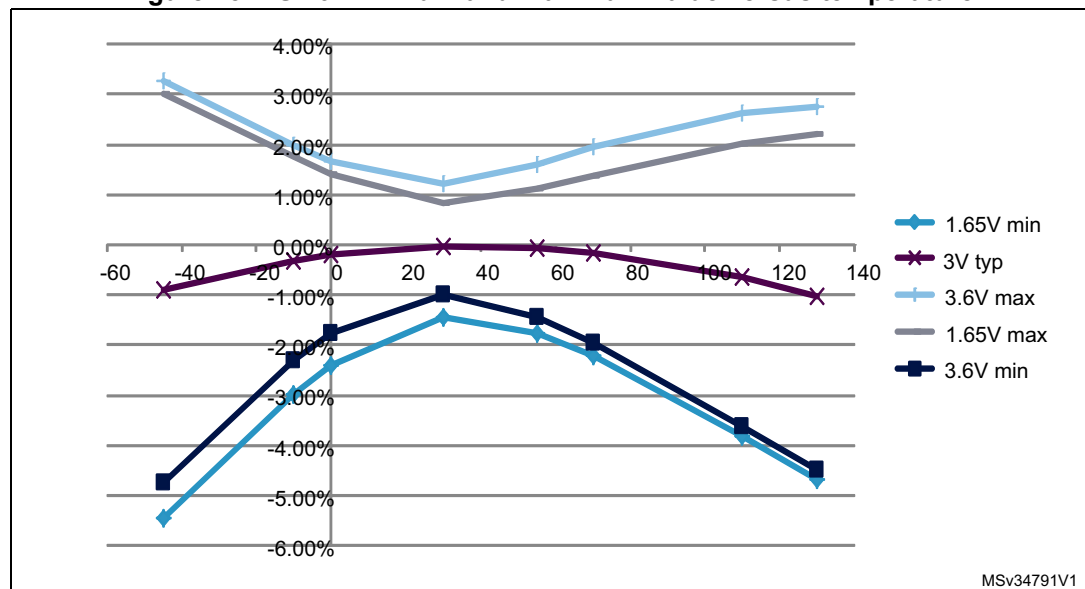
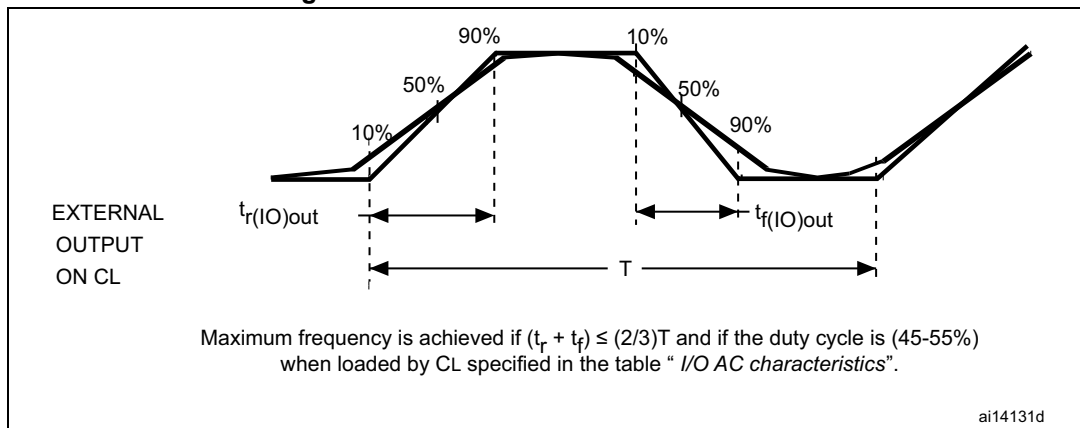


Figure 28. I/O AC characteristics definition



### 6.3.14 NRST pin characteristics

The NRST pin input driver uses CMOS technology. It is connected to a permanent pull-up resistor,  $R_{PU}$ , except when it is internally driven low (see [Table 63](#)).

Unless otherwise specified, the parameters given in [Table 63](#) are derived from tests performed under ambient temperature and  $V_{DD}$  supply voltage conditions summarized in [Table 26](#).

Table 63. NRST pin characteristics

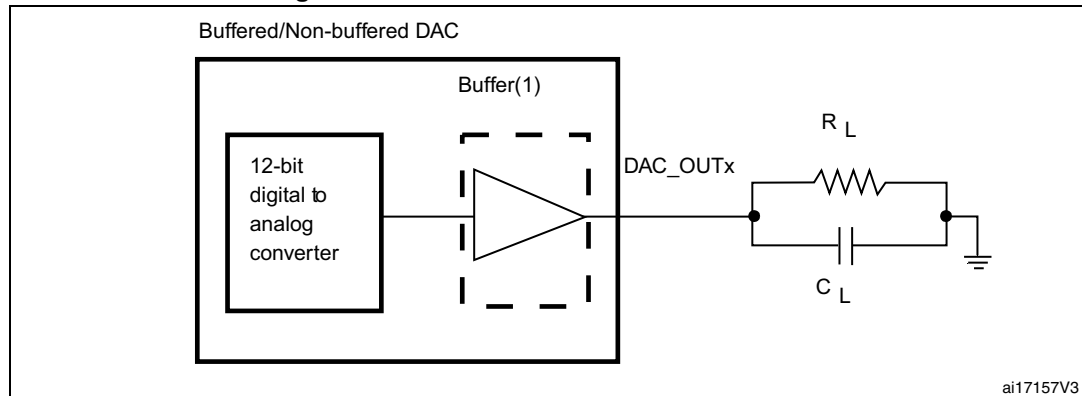
Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{IL(NRST)}^{(1)}$	NRST input low level voltage	-	$V_{SS}$	-	0.8	V
$V_{IH(NRST)}^{(1)}$	NRST input high level voltage	-	1.4	-	$V_{DD}$	
$V_{OL(NRST)}^{(1)}$	NRST output low level voltage	$I_{OL} = 2 \text{ mA}$ $2.7 \text{ V} < V_{DD} < 3.6 \text{ V}$	-	-	0.4	
		$I_{OL} = 1.5 \text{ mA}$ $1.65 \text{ V} < V_{DD} < 2.7 \text{ V}$	-	-		
$V_{hys(NRST)}^{(1)}$	NRST Schmitt trigger voltage hysteresis	-	-	$10\%V_{DD}^{(2)}$	-	mV
$R_{PU}$	Weak pull-up equivalent resistor <sup>(3)</sup>	$V_{IN} = V_{SS}$	30	45	60	$k\Omega$
$V_{F(NRST)}^{(1)}$	NRST input filtered pulse	-	-	-	50	ns
$V_{NF(NRST)}^{(1)}$	NRST input not filtered pulse	-	350	-	-	ns

1. Guaranteed by design.

2. 200 mV minimum value

3. The pull-up is designed with a true resistance in series with a switchable PMOS. This PMOS contribution to the series resistance is around 10%.

6. Difference between the value measured at Code (0x800) and the ideal value =  $V_{REF+}/2$ .
7. Difference between the value measured at Code (0x001) and the ideal value.
8. Difference between ideal slope of the transfer function and measured slope computed from code 0x000 and 0xFF when buffer is off, and from code giving 0.2 V and ( $V_{DDA} - 0.2$ ) V when buffer is on.
9. In buffered mode, the output can overshoot above the final value for low input code (starting from min value).

**Figure 34. 12-bit buffered/non-buffered DAC**

### 6.3.17 Temperature sensor characteristics

**Table 68. Temperature sensor calibration values**

Calibration value name	Description	Memory address
TS_CAL1	TS ADC raw data acquired at temperature of 30 °C, $V_{DDA} = 3$ V	0x1FF8 007A - 0x1FF8 007B
TS_CAL2	TS ADC raw data acquired at temperature of 130 °C, $V_{DDA} = 3$ V	0x1FF8 007E - 0x1FF8 007F

**Table 69. Temperature sensor characteristics**

Symbol	Parameter	Min	Typ	Max	Unit
$T_L^{(1)}$	$V_{SENSE}$ linearity with temperature	-	$\pm 1$	$\pm 2$	°C
Avg_Slope <sup>(1)</sup>	Average slope	1.48	1.61	1.75	mV/°C
$V_{130}$	Voltage at 130°C $\pm 5^\circ\text{C}^{(2)}$	640	670	700	mV
$I_{DDA(TEMP)}^{(3)}$	Current consumption	-	3.4	6	μA
$t_{START}^{(3)}$	Startup time	-	-	10	μs
$T_{S\_temp}^{(4)(3)}$	ADC sampling time when reading the temperature	10	-	-	

1. Guaranteed by characterization results.

2. Measured at  $V_{DD} = 3$  V  $\pm 10$  mV.  $V_{130}$  ADC conversion result is stored in the TS\_CAL2 byte.

3. Guaranteed by design.

4. Shortest sampling time can be determined in the application by multiple iterations.



### 6.3.18 Comparators

**Table 70. Comparator 1 characteristics**

Symbol	Parameter	Conditions	Min <sup>(1)</sup>	Typ	Max <sup>(1)</sup>	Unit
V <sub>DDA</sub>	Analog supply voltage	-	1.65		3.6	V
R <sub>400K</sub>	R <sub>400K</sub> value	-	-	400	-	kΩ
R <sub>10K</sub>	R <sub>10K</sub> value	-	-	10	-	
V <sub>IN</sub>	Comparator 1 input voltage range	-	0.6	-	V <sub>DDA</sub>	V
t <sub>START</sub>	Comparator startup time	-	-	7	10	μs
t <sub>d</sub>	Propagation delay <sup>(2)</sup>	-	-	3	10	
V <sub>offset</sub>	Comparator offset	-	-	±3	±10	mV
d <sub>Voffset</sub> /dt	Comparator offset variation in worst voltage stress conditions	V <sub>DDA</sub> = 3.6 V, V <sub>IN+</sub> = 0 V, V <sub>IN-</sub> = V <sub>REFINT</sub> , T <sub>A</sub> = 25 °C	0	1.5	10	mV/1000 h
I <sub>COMP1</sub>	Current consumption <sup>(3)</sup>	-	-	160	260	nA

1. Guaranteed by characterization.
2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.
3. Comparator consumption only. Internal reference voltage not included.

**Table 71. Comparator 2 characteristics**

Symbol	Parameter	Conditions	Min	Typ	Max <sup>(1)</sup>	Unit
V <sub>DDA</sub>	Analog supply voltage	-	1.65	-	3.6	V
V <sub>IN</sub>	Comparator 2 input voltage range	-	0	-	V <sub>DDA</sub>	V
t <sub>START</sub>	Comparator startup time	Fast mode	-	15	20	μs
		Slow mode	-	20	25	
t <sub>d slow</sub>	Propagation delay <sup>(2)</sup> in slow mode	1.65 V ≤ V <sub>DDA</sub> ≤ 2.7 V	-	1.8	3.5	
		2.7 V ≤ V <sub>DDA</sub> ≤ 3.6 V	-	2.5	6	
t <sub>d fast</sub>	Propagation delay <sup>(2)</sup> in fast mode	1.65 V ≤ V <sub>DDA</sub> ≤ 2.7 V	-	0.8	2	
		2.7 V ≤ V <sub>DDA</sub> ≤ 3.6 V	-	1.2	4	
V <sub>offset</sub>	Comparator offset error		-	±4	±20	mV
dThreshold/dt	Threshold voltage temperature coefficient	V <sub>DDA</sub> = 3.3V, T <sub>A</sub> = 0 to 50 °C, V <sub>-</sub> = V <sub>REFINT</sub> , 3/4 V <sub>REFINT</sub> , 1/2 V <sub>REFINT</sub> , 1/4 V <sub>REFINT</sub>	-	15	30	ppm / °C
I <sub>COMP2</sub>	Current consumption <sup>(3)</sup>	Fast mode	-	3.5	5	μA
		Slow mode	-	0.5	2	

1. Guaranteed by characterization results.
2. The delay is characterized for 100 mV input step with 10 mV overdrive on the inverting input, the non-inverting input set to the reference.
3. Comparator consumption only. Internal reference voltage (required for comparator operation) is not included.

Figure 40. USB timings: definition of data signal rise and fall time

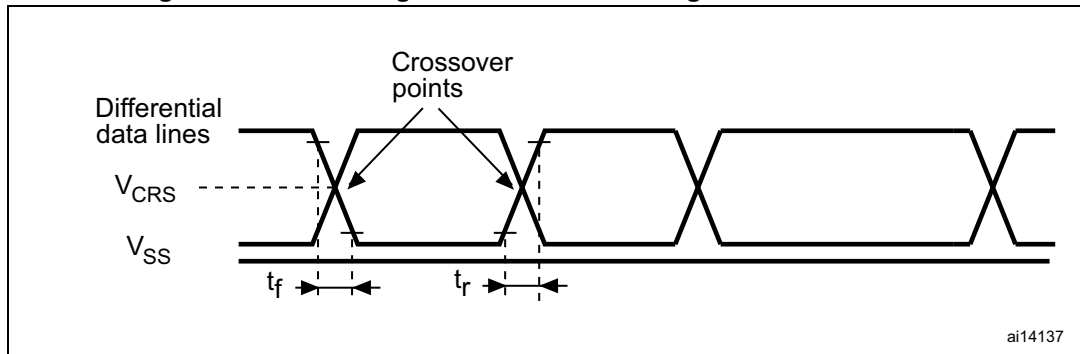


Table 81. USB: full speed electrical characteristics

Driver characteristics <sup>(1)</sup>					
Symbol	Parameter	Conditions	Min	Max	Unit
$t_r$	Rise time <sup>(2)</sup>	$C_L = 50 \text{ pF}$	4	20	ns
$t_f$	Fall Time <sup>(2)</sup>	$C_L = 50 \text{ pF}$	4	20	ns
$t_{rfm}$	Rise/ fall time matching	$t_r/t_f$	90	110	%
$V_{CRS}$	Output signal crossover voltage		1.3	2.0	V

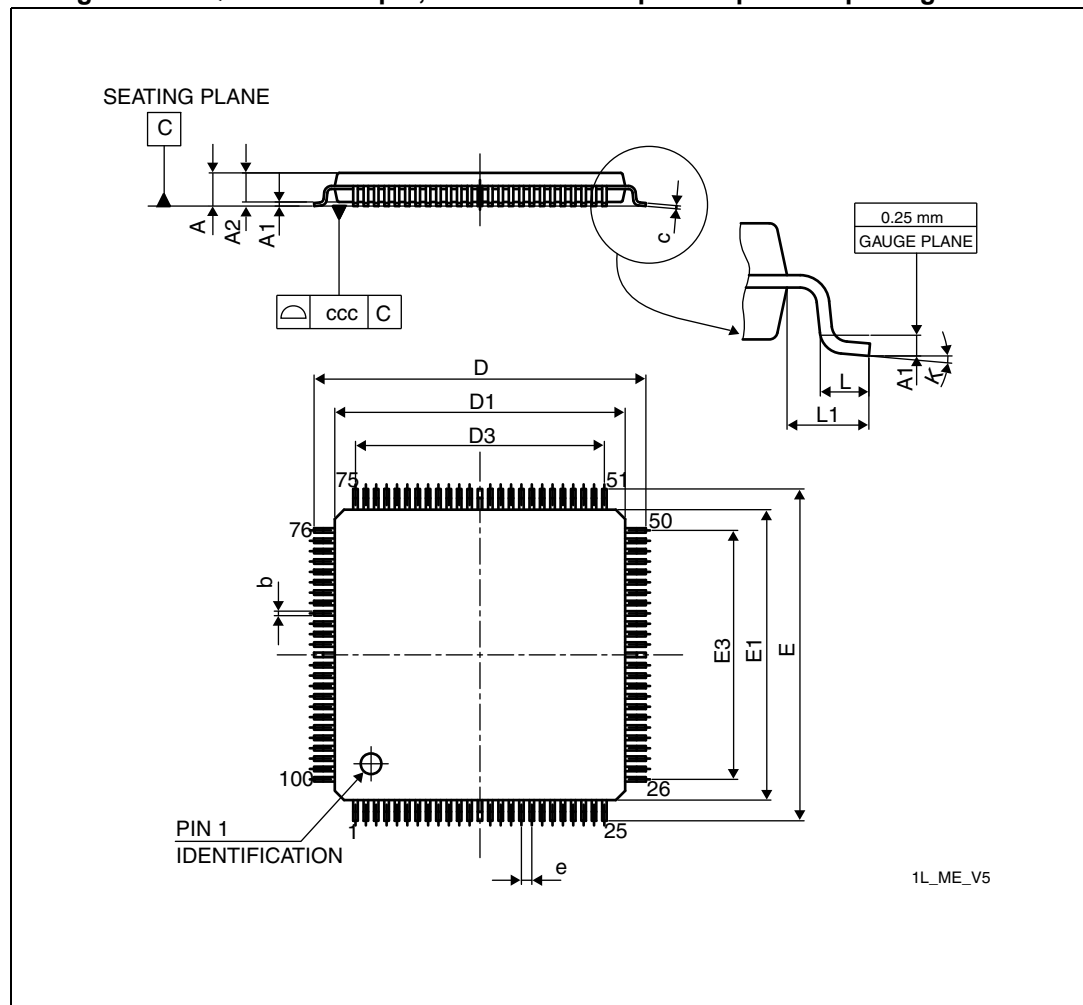
1. Guaranteed by design.
2. Measured from 10% to 90% of the data signal. For more detailed informations, please refer to USB Specification - Chapter 7 (version 2.0).

## 7 Package information

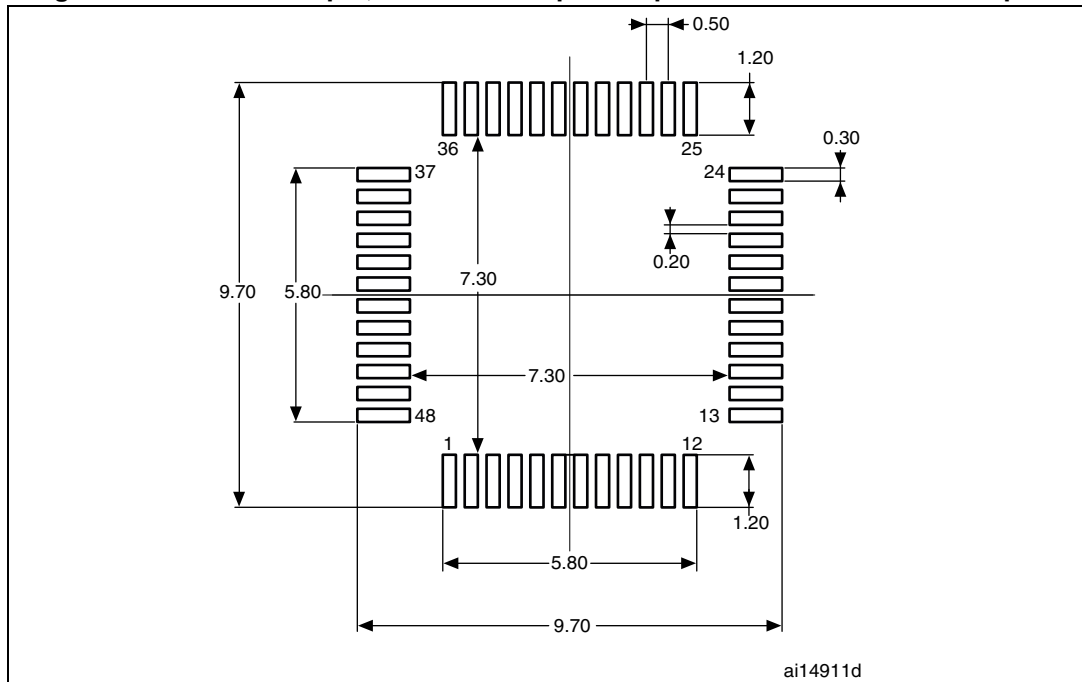
In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status *are available at* [www.st.com](http://www.st.com). ECOPACK® is an ST trademark.

### 7.1 LQFP100 package information

Figure 41. LQFP100 - 100-pin, 14 x 14 mm low-profile quad flat package outline



1. Drawing is not to scale. Dimensions are in millimeters.

**Figure 58. LQFP48 - 48-pin, 7 x 7 mm low-profile quad flat recommended footprint**

1. Dimensions are expressed in millimeters.

## 9 Revision history

**Table 97. Document revision history**

Date	Revision	Changes
02-Sep-2015	1	Initial release
26-Oct-2015	2	<p>Changed confidentiality level to public.</p> <p>Updated datasheet status to “production data”.</p> <p>Modified ultra-low-power platform features on cover page.</p> <p>Added note related to UFQFPN32 in <a href="#">Table 16: STM32L072xxx pin definition</a>.</p> <p>In <a href="#">Section 6: Electrical characteristics</a>, updated notes related to values guaranteed by characterization.</p> <p>Updated <math> \Delta V_{SS} </math> definition to include <math>V_{REF-}</math> in <a href="#">Table 23: Voltage characteristics</a>.</p> <p>Updated <math>f_{TRIG}</math> and <math>V_{AIN}</math> maximum value, added <math>V_{REF+}</math> and <math>V_{REF-}</math> in <a href="#">Table 64: ADC characteristics</a>.</p> <p>Updated <a href="#">Figure 43: UFBGA100 - 100-pin, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package outline</a> and <a href="#">Table 83: UFBGA100 - 100-pin, 7 x 7 mm, 0.50 mm pitch, ultra fine pitch ball grid array package mechanical data</a>.</p> <p>Added <a href="#">Section : Device marking for LQFP64</a>.</p> <p>Add “U” package type in <a href="#">Section 8: Part numbering</a></p>